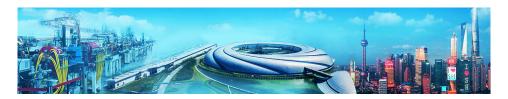
International Workshop on Breakdown Science and High Gradient Technology (HG2018)



Contribution ID: 43 Type: not specified

Dark current fluctuation measurements in RF structures

Thursday 7 June 2018 10:15 (25 minutes)

The dynamics of dislocation activity under intense electric fields has been proposed as a potential cause of breakdowns. In this talk, results of searches for high-frequency fluctuations in field-emitted current that could arise as a consequence of these dynamics are presented for high-gradient RF accelerating structures at CERN. Measurements of spatial profiles of field emission in RF structures and long-term variations are also discussed.

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Session Classification: Breakdown and Experiments